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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

### Applications of "[Embedded - Microcontrollers](#)"

#### Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	80MHz
Connectivity	CANbus, EBI/EMI, I <sup>2</sup> C, IrDA, LINbus, MMC/SD, QSPI, SAI, SPI, SWPMI, UART/USART, USB OTG
Peripherals	Brown-out Detect/Reset, DMA, LCD, PWM, WDT
Number of I/O	83
Program Memory Size	1MB (1M x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	320K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 3.6V
Data Converters	A/D 16x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-LQFP (14x14)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/stmicroelectronics/stm32l4a6vgt6">https://www.e-xfl.com/product-detail/stmicroelectronics/stm32l4a6vgt6</a>

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The Firewall main features are the following:

- Three segments can be protected and defined thanks to the Firewall registers:
  - Code segment (located in Flash or SRAM1 if defined as executable protected area)
  - Non-volatile data segment (located in Flash)
  - Volatile data segment (located in SRAM1)
- The start address and the length of each segments are configurable:
  - Code segment: up to 1024 Kbyte with granularity of 256 bytes
  - Non-volatile data segment: up to 1024 Kbyte with granularity of 256 bytes
  - Volatile data segment: up to 256 Kbyte of SRAM1 with a granularity of 64 bytes
- Specific mechanism implemented to open the Firewall to get access to the protected areas (call gate entry sequence)
- Volatile data segment can be shared or not with the non-protected code
- Volatile data segment can be executed or not depending on the Firewall configuration

The Flash readout protection must be set to level 2 in order to reach the expected level of protection.

### 3.8 Boot modes

At startup, BOOT0 pin and nBOOT1 option bit are used to select one of three boot options:

- Boot from user Flash
- Boot from system memory
- Boot from embedded SRAM

BOOT0 value may come from the PH3-BOOT0 pin or from an option bit depending on the value of a user option bit to free the GPIO pad if needed.

A Flash empty check mechanism is implemented to force the boot from system flash if the first flash memory location is not programmed and if the boot selection is configured to boot from main flash.

The boot loader is located in system memory. It is used to reprogram the Flash memory by using USART, I2C, SPI, CAN or USB OTG FS in Device mode through DFU (device firmware upgrade).

### 3.9 Cyclic redundancy check calculation unit (CRC)

The CRC (cyclic redundancy check) calculation unit is used to get a CRC code using a configurable generator polynomial value and size.

Among other applications, CRC-based techniques are used to verify data transmission or storage integrity. In the scope of the EN/IEC 60335-1 standard, they offer a means of verifying the Flash memory integrity. The CRC calculation unit helps compute a signature of the software during runtime, to be compared with a reference signature generated at link-time and stored at a given memory location.

- **Shutdown mode**

The Shutdown mode allows to achieve the lowest power consumption. The internal regulator is switched off so that the  $V_{\text{CORE}}$  domain is powered off. The PLL, the HSI16, the MSI, the LSI and the HSE oscillators are also switched off.

The RTC can remain active (Shutdown mode with RTC, Shutdown mode without RTC).

The BOR is not available in Shutdown mode. No power voltage monitoring is possible in this mode, therefore the switch to Backup domain is not supported.

SRAM1, SRAM2 and register contents are lost except for registers in the Backup domain.

The device exits Shutdown mode when an external reset (NRST pin), a WKUP pin event (configurable rising or falling edge), or an RTC event occurs (alarm, periodic wakeup, timestamp, tamper).

The system clock after wakeup is MSI at 4 MHz.

The main features of the touch sensing controller are the following:

- Proven and robust surface charge transfer acquisition principle
- Supports up to 24 capacitive sensing channels
- Up to 3 capacitive sensing channels can be acquired in parallel offering a very good response time
- Spread spectrum feature to improve system robustness in noisy environments
- Full hardware management of the charge transfer acquisition sequence
- Programmable charge transfer frequency
- Programmable sampling capacitor I/O pin
- Programmable channel I/O pin
- Programmable max count value to avoid long acquisition when a channel is faulty
- Dedicated end of acquisition and max count error flags with interrupt capability
- One sampling capacitor for up to 3 capacitive sensing channels to reduce the system components
- Compatible with proximity, touchkey, linear and rotary touch sensor implementation
- Designed to operate with STMTouch touch sensing firmware library

*Note:* The number of capacitive sensing channels is dependent on the size of the packages and subject to I/O availability.

### 3.23 Liquid crystal display controller (LCD)

The LCD drives up to 8 common terminals and 44 segment terminals to drive up to 320 pixels.

- Internal step-up converter to guarantee functionality and contrast control irrespective of  $V_{DD}$ . This converter can be deactivated, in which case the VLCD pin is used to provide the voltage to the LCD
- Supports static, 1/2, 1/3, 1/4 and 1/8 duty
- Supports static, 1/2, 1/3 and 1/4 bias
- Phase inversion to reduce power consumption and EMI
- Integrated voltage output buffers for higher LCD driving capability
- Up to 8 pixels can be programmed to blink
- Unneeded segments and common pins can be used as general I/O pins
- LCD RAM can be updated at any time owing to a double-buffer
- The LCD controller can operate in Stop mode

### 3.24 Digital filter for Sigma-Delta Modulators (DFSDM)

The device embeds one DFSDM with 4 digital filters modules and 8 external input serial channels (transceivers) or alternately 8 internal parallel inputs support.

The DFSDM peripheral is dedicated to interface the external  $\Sigma\Delta$  modulators to microcontroller and then to perform digital filtering of the received data streams (which represent analog value on  $\Sigma\Delta$  modulators inputs). DFSDM can also interface PDM (Pulse Density Modulation) microphones and perform PDM to PCM conversion and filtering in

### 3.28 HASH hardware accelerator (HASH)

The hash processor is a fully compliant implementation of the secure hash algorithm (SHA-1, SHA-224, SHA-256), the MD5 (message-digest algorithm 5) hash algorithm and the HMAC (keyed-hash message authentication code) algorithm suitable for a variety of applications.

It computes a message digest (160 bits for the SHA-1 algorithm, 256 bits for the SHA-256 algorithm and 224 bits for the SHA-224 algorithm, 128 bits for the MD5 algorithm) for messages of up to (264 - 1) bits, while HMAC algorithms provide a way of authenticating messages by means of hash functions. HMAC algorithms consist in calling the SHA-1, SHA-224, SHA-256 or MD5 hash function twice.

### 3.29 Timers and watchdogs

The STM32L4A6xG includes two advanced control timers, up to nine general-purpose timers, two basic timers, two low-power timers, two watchdog timers and a SysTick timer. The table below compares the features of the advanced control, general purpose and basic timers.

**Table 10. Timer feature comparison**

Timer type	Timer	Counter resolution	Counter type	Prescaler factor	DMA request generation	Capture/compare channels	Complementary outputs
Advanced control	TIM1, TIM8	16-bit	Up, down, Up/down	Any integer between 1 and 65536	Yes	4	3
General-purpose	TIM2, TIM5	32-bit	Up, down, Up/down	Any integer between 1 and 65536	Yes	4	No
General-purpose	TIM3, TIM4	16-bit	Up, down, Up/down	Any integer between 1 and 65536	Yes	4	No
General-purpose	TIM15	16-bit	Up	Any integer between 1 and 65536	Yes	2	1
General-purpose	TIM16, TIM17	16-bit	Up	Any integer between 1 and 65536	Yes	1	1
Basic	TIM6, TIM7	16-bit	Up	Any integer between 1 and 65536	Yes	0	No

#### 3.29.1 Advanced-control timer (TIM1, TIM8)

The advanced-control timer can each be seen as a three-phase PWM multiplexed on 6 channels. They have complementary PWM outputs with programmable inserted dead-

### 3.33 Low-power universal asynchronous receiver transmitter (LPUART)

The device embeds one Low-Power UART. The LPUART supports asynchronous serial communication with minimum power consumption. It supports half duplex single wire communication and modem operations (CTS/RTS). It allows multiprocessor communication.

The LPUART has a clock domain independent from the CPU clock, and can wakeup the system from Stop mode using baudrates up to 220 Kbaud. The wake up events from Stop mode are programmable and can be:

- Start bit detection
- Any received data frame
- A specific programmed data frame

Only a 32.768 kHz clock (LSE) is needed to allow LPUART communication up to 9600 baud. Therefore, even in Stop mode, the LPUART can wait for an incoming frame while having an extremely low energy consumption. Higher speed clock can be used to reach higher baudrates.

LPUART interface can be served by the DMA controller.



Table 14. Legend/abbreviations used in the pinout table

Name		Abbreviation	Definition
Pin name		Unless otherwise specified in brackets below the pin name, the pin function during and after reset is the same as the actual pin name	
Pin type		S	Supply pin
		I	Input only pin
		I/O	Input / output pin
I/O structure		FT	5 V tolerant I/O
		TT	3.6 V tolerant I/O
		RST	Bidirectional reset pin with embedded weak pull-up resistor
		Option for TT or FT I/Os	
		_f <sup>(1)</sup>	I/O, Fm+ capable
		_l <sup>(2)</sup>	I/O, with LCD function supplied by V <sub>LCD</sub>
		_u <sup>(3)</sup>	I/O, with USB function supplied by V <sub>DDUSB</sub>
		_a <sup>(4)</sup>	I/O, with Analog switch function supplied by V <sub>DDA</sub>
		_s <sup>(5)</sup>	I/O supplied only by V <sub>DDIO2</sub>
Notes		Unless otherwise specified by a note, all I/Os are set as analog inputs during and after reset.	
Pin functions	Alternate functions	Functions selected through GPIOx_AFR registers	
	Additional functions	Functions directly selected/enabled through peripheral registers	

1. The related I/O structures in [Table 15](#) are: FT\_f, FT\_fa, FT\_fl, FT fla.
2. The related I/O structures in [Table 15](#) are: FT\_l, FT\_fl, FT\_lu.
3. The related I/O structures in [Table 15](#) are: FT\_u, FT\_lu.
4. The related I/O structures in [Table 15](#) are: FT\_a, FT\_la, FT\_fa, FT fla, TT\_a, TT\_la.
5. The related I/O structures in [Table 15](#) are: FT\_s, FT\_fs.



Table 15. STM32L4A6xG pin definitions (continued)

Pin Number										Pin name (function after reset)	Pin type	I/O structure	Notes	Pin functions	
LQFP64	WLCSP100	WLCSP100_SMPS	LQFP100	UFBGA132	UFBGA132_SMPS	LQFP144	LQFP144_SMPS	UFBGA169	UFBGA169_SMPS					Alternate functions	Additional functions
-	-	-	-	-	-	21	21	-	-	PF9	I/O	FT_a	-	TIM5_CH4, QUADSPI_BK1_IO1, SAI1_FS_B, TIM15_CH1, EVENTOUT	ADC3_IN12
-	-	-	-	-	-	22	22	H4	H4	PF10	I/O	FT_a	-	QUADSPI_CLK, DCMI_D11, TIM15_CH2, EVENTOUT	ADC3_IN13
5	F10	F10	12	F1	F1	23	23	H1	H1	PH0-OSC_IN (PH0)	I/O	FT	-	EVENTOUT	OSC_IN
6	G10	F9	13	G1	G1	24	24	J1	J1	PH1-OSC_OUT (PH1)	I/O	FT	-	EVENTOUT	OSC_OUT
7	E8	F8	14	H2	H2	25	25	H3	H3	NRST	I/O	RST	-	-	-
8	F9	G10	15	H1	H1	26	26	J2	J2	PC0	I/O	FT fla	-	LPTIM1_IN1, I2C4_SCL, I2C3_SCL, DFSDM1_DATIN4, LPUART1_RX, LCD_SEG18, LPTIM2_IN1, EVENTOUT	ADC123_IN1
9	F8	F7	16	J2	J2	27	27	J3	J3	PC1	I/O	FT fla	-	TRACED0, LPTIM1_OUT, I2C4_SDA, SPI2_MOSI, I2C3_SDA, DFSDM1_CKIN4, LPUART1_TX, QUADSPI_BK2_IO0, LCD_SEG19, SAI1_SD_A, EVENTOUT	ADC123_IN2
10	H10	G9	17	J3	J3	28	28	J4	J4	PC2	I/O	FT la	-	LPTIM1_IN2, SPI2_MISO, DFSDM1_CKOUT, QUADSPI_BK2_IO1, LCD_SEG20, EVENTOUT	ADC123_IN3
11	F7	F6	18	K2	K2	29	29	K1	K1	PC3	I/O	FT la	-	LPTIM1_ETR, SPI2_MOSI, QUADSPI_BK2_IO2, LCD_VLCD, SAI1_SD_A, LPTIM2_ETR, EVENTOUT	ADC123_IN4



Table 15. STM32L4A6xG pin definitions (continued)

Pin Number										Pin name (function after reset)	Pin type	I/O structure	Notes	Pin functions	
LQFP64	WLCSP100	WLCSP100_SMPS	LQFP100	UFBGA132	UFBGA132_SMPS	LQFP144	LQFP144_SMPS	UFBGA169	UFBGA169_SMPS					Alternate functions	Additional functions
55	C6	F5	89	A8	A8	133	132	A6	A6	PB3 (JTDO/TRACES WO)	I/O	FT_la	(4)	JTDO/TRACESWO, TIM2_CH2, SPI1_SCK, SPI3_SCK, USART1_RTS_DE, OTG_FS_CRD_SYNC, LCD_SEG7, SAI1_SCK_B, EVENTOUT	COMP2_INM
56	C7	E6	90	A7	A7	134	133	A5	A5	PB4 (NJTRST)	I/O	FT fla	(4)	NJTRST, TIM3_CH1, I2C3_SDA, SPI1_MISO, SPI3_MISO, USART1_CTS, UART5_RTS_DE, TSC_G2_IO1, DCM1_D12, LCD_SEG8, SAI1_MCLK_B, TIM17_BKIN, EVENTOUT	COMP2_INP
57	B7	C7	91	C5	C5	135	134	B5	B5	PB5	I/O	FT_la	-	LPTIM1_IN1, TIM3_CH2, CAN2_RX, I2C1_SMBA, SPI1_MOSI, SPI3_MOSI, USART1_CK, UART5_CTS, TSC_G2_IO2, DCM1_D10, LCD_SEG9, COMP2_OUT, SAI1_SD_B, TIM16_BKIN, EVENTOUT	-
58	A7	A7	92	B5	B5	136	135	C5	C5	PB6	I/O	FT_fa	-	LPTIM1_ETR, TIM4_CH1, TIM8_BKIN2, I2C1_SCL, I2C4_SCL, DFSDM1_DATIN5, USART1_TX, CAN2_TX, TSC_G2_IO3, DCM1_D5, TIM8_BKIN2_COMP2, SAI1_FS_B, TIM16_CH1N, EVENTOUT	COMP2_INP

Table 17. Alternate function AF8 to AF15<sup>(1)</sup> (continued)

Port		AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
		UART4/5/ LPUART1/ CAN2	CAN1/TSC	CAN2/ OTG_FS/DCMI/ QUADSPI	LCD	SDMMC/ COMP1/2/FM C/SWPMI1	SAI1/2	TIM2/15/16/17/ LPTIM2	EVENOUT
Port G	PG0	-	TSC_G8_IO3	-	-	FMC_A10	-	-	EVENTOUT
	PG1	-	TSC_G8_IO4	-	-	FMC_A11	-	-	EVENTOUT
	PG2	-	-	-	-	FMC_A12	SAI2_SCK_B	-	EVENTOUT
	PG3	-	-	-	-	FMC_A13	SAI2_FS_B	-	EVENTOUT
	PG4	-	-	-	-	FMC_A14	SAI2_MCLK_B	-	EVENTOUT
	PG5	LPUART1_CTS	-	-	-	FMC_A15	SAI2_SD_B	-	EVENTOUT
	PG6	LPUART1_RTS_DE	-	-	-	-	-	-	EVENTOUT
	PG7	LPUART1_TX	-	-	-	FMC_INT	SAI1_MCLK_A	-	EVENTOUT
	PG8	LPUART1_RX	-	-	-	-	-	-	EVENTOUT
	PG9	-	-	-	-	FMC_NCE/FMC_NE2	SAI2_SCK_A	TIM15_CH1N	EVENTOUT
	PG10	-	-	-	-	FMC_NE3	SAI2_FS_A	TIM15_CH1	EVENTOUT
	PG11	-	-	-	-	-	SAI2_MCLK_A	TIM15_CH2	EVENTOUT
	PG12	-	-	-	-	FMC_NE4	SAI2_SD_A	-	EVENTOUT
	PG13	-	-	-	-	FMC_A24	-	-	EVENTOUT
	PG14	-	-	-	-	FMC_A25	-	-	EVENTOUT
	PG15	-	-	DCMI_D13	-	-	-	-	EVENTOUT

Table 22. General operating conditions (continued)

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>BAT</sub>	Backup operating voltage	-	1.55	3.6	V
V <sub>DDUSB</sub>	USB supply voltage	USB used	3.0	3.6	
		USB not used	0	3.6	
V <sub>IN</sub>	I/O input voltage	TT_xx I/O	-0.3	V <sub>DDIOx</sub> +0.3	
		BOOT0	0	9	
		All I/O except BOOT0 and TT_xx	-0.3	Min(Min(V <sub>DD</sub> , V <sub>DDA</sub> , V <sub>DDIO2</sub> , V <sub>DDUSB</sub> , V <sub>LCD</sub> )+3.6 V, 5.5 V) <sup>(2)(3)</sup>	
P <sub>D</sub>	Power dissipation at T <sub>A</sub> = 85 °C for suffix 6 <sup>(4)</sup>	LQFP144	-	625	mW
		LQFP100	-	476	
		LQFP64	-	444	
		UFBGA169	-	385	
		UFBGA132	-	364	
		WLCSP100	-	559	
P <sub>D</sub>	Power dissipation at T <sub>A</sub> = 125 °C for suffix 3 <sup>(4)</sup>	LQFP144	-	156	mW
		LQFP100	-	119	
		LQFP64	-	111	
		UFBGA169	-	96	
		UFBGA132	-	91	
		WLCSP100	-	140	
T <sub>A</sub>	Ambient temperature for the suffix 6 version	Maximum power dissipation	-40	85	°C
		Low-power dissipation <sup>(5)</sup>	-40	105	
	Ambient temperature for the suffix 3 version	Maximum power dissipation	-40	125	
		Low-power dissipation <sup>(5)</sup>	-40	130	
T <sub>J</sub>	Junction temperature range	Suffix 6 version	-40	105	°C
		Suffix 3 version	-40	130	

1. When RESET is released functionality is guaranteed down to V<sub>BOR0</sub> Min.
2. This formula has to be applied only on the power supplies related to the IO structure described by the pin definition table. Maximum I/O input voltage is the smallest value between Min(V<sub>DD</sub>, V<sub>DDA</sub>, V<sub>DDIO2</sub>, V<sub>DDUSB</sub>, V<sub>LCD</sub>)+3.6 V and 5.5V.
3. For operation with voltage higher than Min (V<sub>DD</sub>, V<sub>DDA</sub>, V<sub>DDIO2</sub>, V<sub>DDUSB</sub>, V<sub>LCD</sub>) +0.3 V, the internal Pull-up and Pull-Down resistors must be disabled.
4. If T<sub>A</sub> is lower, higher P<sub>D</sub> values are allowed as long as T<sub>J</sub> does not exceed T<sub>Jmax</sub> (see [Section 7.7: Thermal characteristics](#)).
5. In low-power dissipation state, T<sub>A</sub> can be extended to this range as long as T<sub>J</sub> does not exceed T<sub>Jmax</sub> (see [Section 7.7: Thermal characteristics](#)).



**Table 27. Current consumption in Run modes, code with data processing running from Flash,  
(ART enable Cache ON Prefetch OFF) and power supplied  
(by external SMPS ( $V_{DD12} = 1.10$  V))**

Symbol	Parameter	Conditions <sup>(1)</sup>		TYP					Unit
		-	$f_{HCLK}$	25 °C	55 °C	85 °C	105 °C	125 °C	
$I_{DD\_ALL}(Run)$	Supply current in Run mode	$f_{HCLK} = f_{HSE}$ up to 48MHz included, bypass mode PLL ON above 48 MHz all peripherals disable	80 MHz	3.39	3.42	3.48	3.57	3.74	mA
			72 MHz	3.06	3.09	3.15	3.24	3.43	
			64 MHz	2.74	2.76	2.81	2.91	3.10	
			48 MHz	2.06	2.08	2.14	2.23	2.42	
			32 MHz	1.39	1.41	1.46	1.56	1.74	
			24 MHz	1.06	1.07	1.13	1.22	1.40	
			16 MHz	0.72	0.74	0.79	0.88	1.06	
			8 MHz	0.39	0.41	0.46	0.56	0.75	
			4 MHz	0.22	0.24	0.29	0.39	0.58	
			2 MHz	0.14	0.16	0.21	0.30	0.50	
			1 MHz	0.10	0.11	0.16	0.26	0.46	
			100 kHz	0.06	0.07	0.13	0.22	0.42	

1. All values are obtained by calculation based on measurements done without SMPS and using following parameters: SMPS input = 3.3 V, SMPS efficiency = 85%,  $V_{DD12} = 1.10$  V

### 6.3.8 Internal clock source characteristics

The parameters given in [Table 58](#) are derived from tests performed under ambient temperature and supply voltage conditions summarized in [Table 22: General operating conditions](#). The provided curves are characterization results, not tested in production.

#### High-speed internal (HSI16) RC oscillator

**Table 58. HSI16 oscillator characteristics<sup>(1)</sup>**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$f_{\text{HSI16}}$	HSI16 Frequency	$V_{\text{DD}}=3.0\text{ V}$ , $T_{\text{A}}=30\text{ °C}$	15.88	-	16.08	MHz
TRIM	HSI16 user trimming step	Trimming code is not a multiple of 64	0.2	0.3	0.4	%
		Trimming code is a multiple of 64	-4	-6	-8	
$\text{DuCy}(\text{HSI16})^{(2)}$	Duty Cycle	-	45	-	55	%
$\Delta_{\text{Temp}}(\text{HSI16})$	HSI16 oscillator frequency drift over temperature	$T_{\text{A}}=0\text{ to }85\text{ °C}$	-1	-	1	%
		$T_{\text{A}}=-40\text{ to }125\text{ °C}$	-2	-	1.5	%
$\Delta_{\text{VDD}}(\text{HSI16})$	HSI16 oscillator frequency drift over $V_{\text{DD}}$	$V_{\text{DD}}=1.62\text{ V to }3.6\text{ V}$	-0.1	-	0.05	%
$t_{\text{su}}(\text{HSI16})^{(2)}$	HSI16 oscillator start-up time	-	-	0.8	1.2	$\mu\text{s}$
$t_{\text{stab}}(\text{HSI16})^{(2)}$	HSI16 oscillator stabilization time	-	-	3	5	$\mu\text{s}$
$I_{\text{DD}}(\text{HSI16})^{(2)}$	HSI16 oscillator power consumption	-	-	155	190	$\mu\text{A}$

1. Guaranteed by characterization results.

2. Guaranteed by design.

### Static latch-up

Two complementary static tests are required on six parts to assess the latch-up performance:

- A supply overvoltage is applied to each power supply pin.
- A current injection is applied to each input, output and configurable I/O pin.

These tests are compliant with EIA/JESD 78A IC latch-up standard.

**Table 68. Electrical sensitivities**

Symbol	Parameter	Conditions	Class
LU	Static latch-up class	$T_A = +105\text{ }^{\circ}\text{C}$ conforming to JESD78A	II level A <sup>(1)</sup>

1. Negative injection is limited to -30 mA for PF0, PF1, PG6, PG7, PG8, PG12, PG13, PG14.

### 6.3.13 I/O current injection characteristics

As a general rule, current injection to the I/O pins, due to external voltage below  $V_{SS}$  or above  $V_{DDIOx}$  (for standard, 3.3 V-capable I/O pins) should be avoided during normal product operation. However, in order to give an indication of the robustness of the microcontroller in cases when abnormal injection accidentally happens, susceptibility tests are performed on a sample basis during device characterization.

#### Functional susceptibility to I/O current injection

While a simple application is executed on the device, the device is stressed by injecting current into the I/O pins programmed in floating input mode. While current is injected into the I/O pin, one at a time, the device is checked for functional failures.

The failure is indicated by an out of range parameter: ADC error above a certain limit (higher than 5 LSB TUE), out of conventional limits of induced leakage current on adjacent pins (out of the -5  $\mu\text{A}$ /+0  $\mu\text{A}$  range) or other functional failure (for example reset occurrence or oscillator frequency deviation).

The characterization results are given in [Table 69](#).

Negative induced leakage current is caused by negative injection and positive induced leakage current is caused by positive injection.

**Table 69. I/O current injection susceptibility<sup>(1)</sup>**

Symbol	Description	Functional susceptibility		Unit
		Negative injection	Positive injection	
$I_{INJ}$	Injected current on all pins except PA4, PA5, PB0, PF12, PF13, OPAMP1_V1NM, OPAMP2_V1NM	-5	NA <sup>(2)</sup>	mA
	Injected current on pins PB0, PF12, PF13	0	NA <sup>(2)</sup>	
	Injected current on OPAMP1_V1NM, OPAMP2_V1NM	0	0	
	Injected current on PA4, PA5 pins	-5	0	

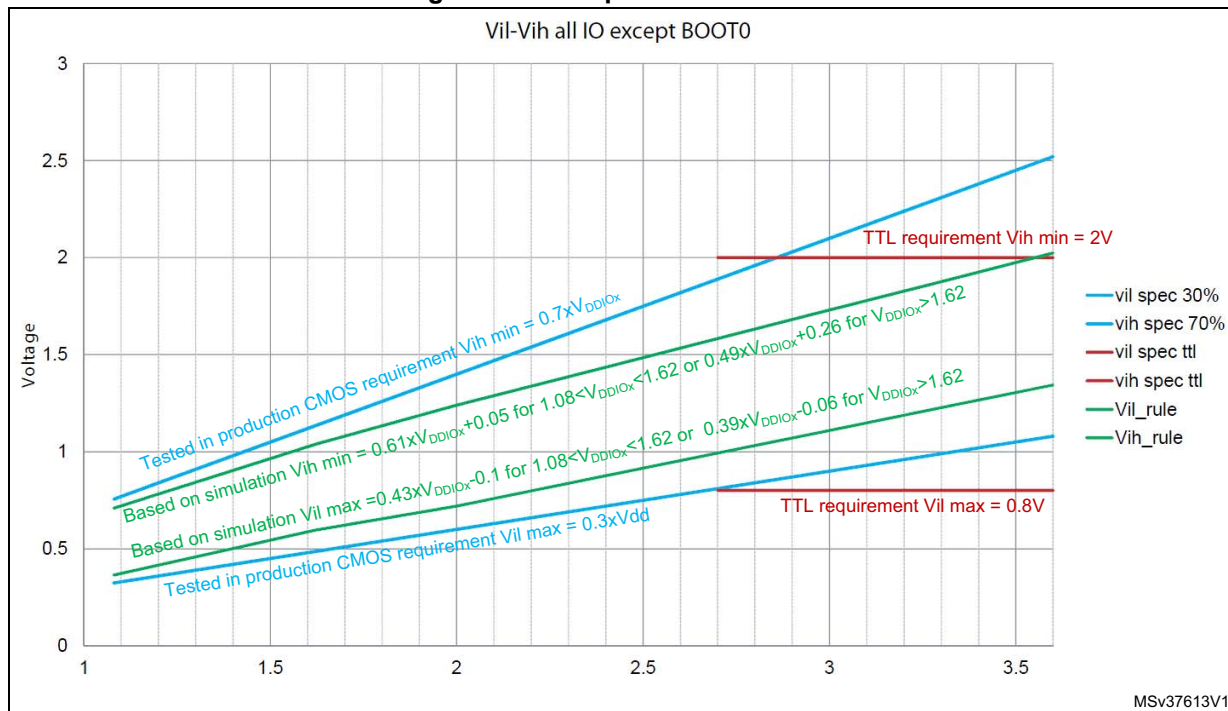
1. Guaranteed by characterization.

2. Injection is not possible



All I/Os are CMOS- and TTL-compliant (no software configuration required). Their characteristics cover more than the strict CMOS-technology or TTL parameters. The coverage of these requirements is shown in [Figure 30](#) for standard I/Os, and in [Figure 30](#) for 5 V tolerant I/Os.

**Figure 30. I/O input characteristics**



### Output driving current

The GPIOs (general purpose input/outputs) can sink or source up to  $\pm 8$  mA, and sink or source up to  $\pm 20$  mA (with a relaxed  $V_{OL}/V_{OH}$ ).

In the user application, the number of I/O pins which can drive current must be limited to respect the absolute maximum rating specified in [Section 6.2](#):

- The sum of the currents sourced by all the I/Os on  $V_{DDIOX}$ , plus the maximum consumption of the MCU sourced on  $V_{DD}$ , cannot exceed the absolute maximum rating  $\Sigma I_{VDD}$  (see [Table 19: Voltage characteristics](#)).
- The sum of the currents sunk by all the I/Os on  $V_{SS}$ , plus the maximum consumption of the MCU sunk on  $V_{SS}$ , cannot exceed the absolute maximum rating  $\Sigma I_{VSS}$  (see [Table 19: Voltage characteristics](#)).

2. The I/O analog switch voltage booster is enable when  $V_{DDA} < 2.4\text{ V}$  (BOOSTEN = 1 in the SYSCFG\_CFGR1 when  $V_{DDA} < 2.4\text{V}$ ). It is disable when  $V_{DDA} \geq 2.4\text{ V}$ .
3. Fast channels are: PC0, PC1, PC2, PC3, PA0.
4. Slow channels are: all ADC inputs except the fast channels.

## 6.3.28 Communication interfaces characteristics

### I<sup>2</sup>C interface characteristics

The I2C interface meets the timings requirements of the I<sup>2</sup>C-bus specification and user manual rev. 03 for:

- Standard-mode (Sm): with a bit rate up to 100 kbit/s
- Fast-mode (Fm): with a bit rate up to 400 kbit/s
- Fast-mode Plus (Fm+): with a bit rate up to 1 Mbit/s.

The I2C timings requirements are guaranteed by design when the I2C peripheral is properly configured (refer to RM0351 reference manual).

The SDA and SCL I/O requirements are met with the following restrictions: the SDA and SCL I/O pins are not “true” open-drain. When configured as open-drain, the PMOS connected between the I/O pin and V<sub>DDIOx</sub> is disabled, but is still present. Only FT\_f I/O pins support Fm+ low level output current maximum requirement. Refer to [Section 6.3.14: I/O port characteristics](#) for the I2C I/Os characteristics.

All I2C SDA and SCL I/Os embed an analog filter. Refer to the table below for the analog filter characteristics:

**Table 95. I2C analog filter characteristics<sup>(1)</sup>**

Symbol	Parameter	Min	Max	Unit
t <sub>AF</sub>	Maximum pulse width of spikes that are suppressed by the analog filter	50 <sup>(2)</sup>	260 <sup>(3)</sup>	ns

1. Guaranteed by design.
2. Spikes with widths below t<sub>AF(min)</sub> are filtered.
3. Spikes with widths above t<sub>AF(max)</sub> are not filtered

Figure 39. Quad SPI timing diagram - SDR mode

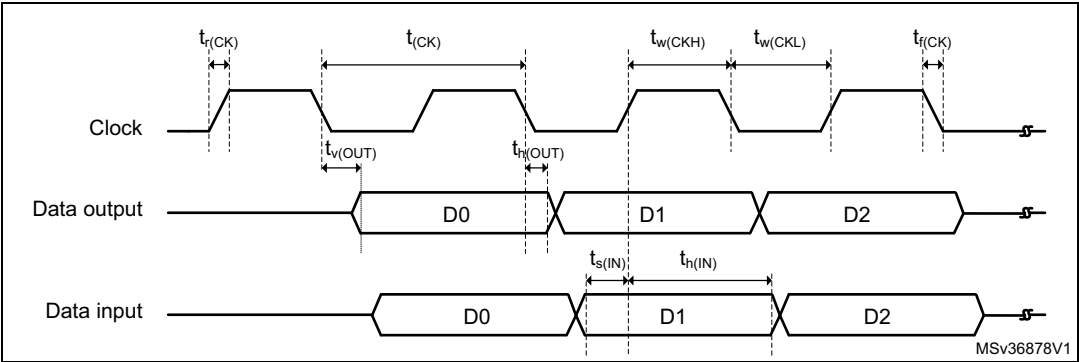
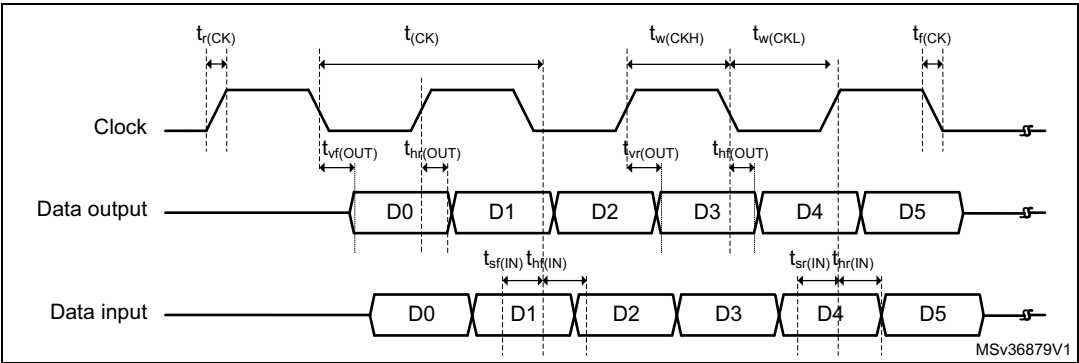


Figure 40. Quad SPI timing diagram - DDR mode

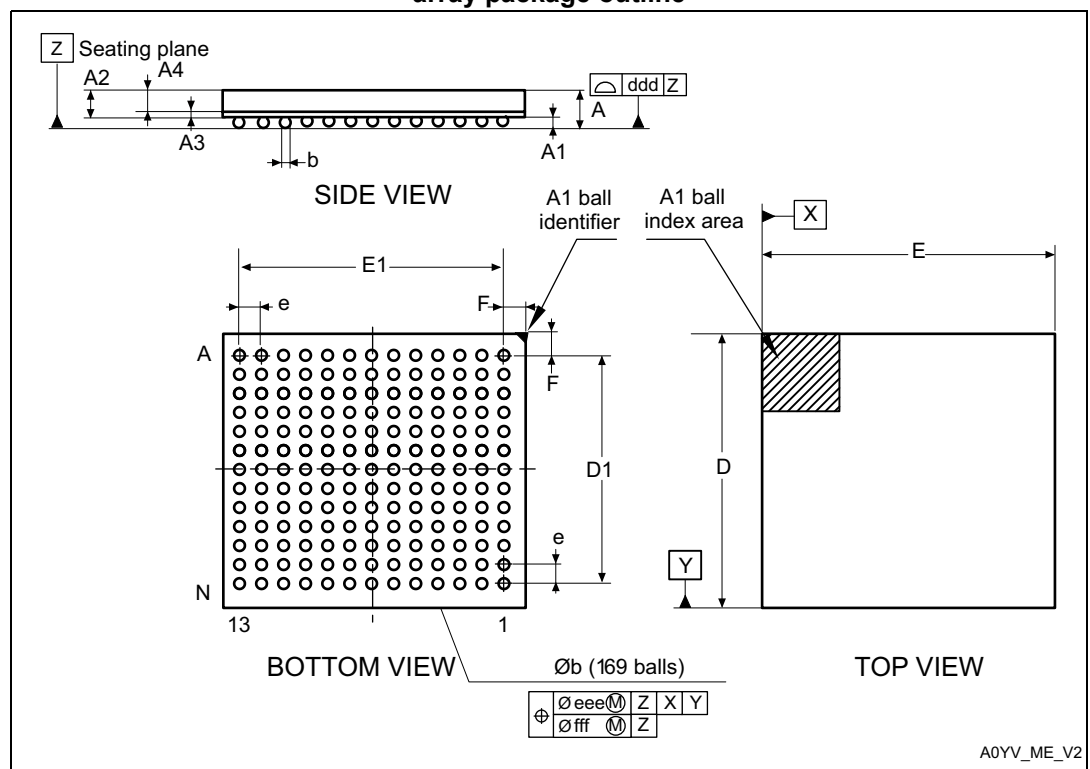


## 7 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK® is an ST trademark.

### 7.1 UFBGA169 package information

**Figure 61. UFBGA169 - 169-ball, 7 x 7 mm, 0.50 mm pitch, ultra fine pitch ball grid array package outline**



**Table 123. UFBGA169 - 169-ball, 7 x 7 mm, 0.50 mm pitch, ultra fine pitch ball grid array package mechanical data**

Symbol	millimeters			inches <sup>(1)</sup>		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	0.460	0.530	0.600	0.0181	0.0209	0.0236
A1	0.050	0.080	0.110	0.0020	0.0031	0.0043
A2	0.400	0.450	0.500	0.0157	0.0177	0.0197
A3	-	0.130	-	-	0.0051	-
A4	0.270	0.320	0.370	0.0106	0.0126	0.0146